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LIST OF PATENTS AND
PUBLICATIONS
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DISCLOSURE STATEMENT

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APPLICANT: BELLMAN ROBERT A, et al.

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GROUP: Unknown

REFERENCE DESIGNATION

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Examiner Initial		Document Number	Date	Name	Class	Sub-Class	Filing Date if Approp.
<i>AR</i>	AA	2001/0024701	9/27/01	Matsukura et al	428	14	3/13/01
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<i>AR</i>	AM	Bruel et al; "Smart Cut: A Promising New Soi Material Technology"; IEEE International SOI Conference; Oct. 1995; pages 178-179.
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<i>AR</i>	AQ	Gosele et al.; "Wafer Bonding: An Overview"; Proceedings of 4th International Conference on Solid-State and IC Technology; 1995; pages 243-247
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EXAMINER:

A. Rosasco

DATE CONSIDERED:

2/06

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609: draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.